- EPIC™ (Enhanced-Performance Implanted CMOS) 1-μm Process
- Package Options Include Plastic Small-Outline (D), Shrink Small-Outline (DB), and Thin Shrink Small-Outline (PW) Packages, Ceramic Chip Carriers (FK) and Flatpacks (W), and Standard Plastic (N) and Ceramic (J) DIPS

description

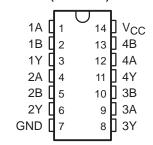
The 'AC32 are quadruple 2-input positive-OR gates. The devices perform the Boolean function Y = A + B or $Y = \overline{A} \bullet \overline{B}$ in positive logic.

The SN54AC32 is characterized for operation over the full military temperature range of -55° C to 125°C. The SN74AC32 is characterized for operation from -40° C to 85°C.

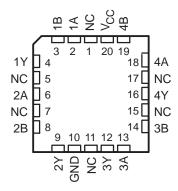
FUNCTION TABLE (each gate)

INP	UTS	OUTPUT
Α	В	Y
Н	Χ	Н
X	Н	Н
L	L	L

SN54AC32...J OR W PACKAGE SN74AC32...D, DB, N, OR PW PACKAGE (TOP VIEW)

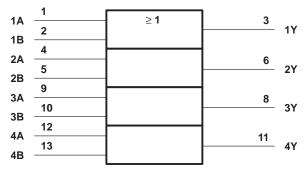


SN54AC32 . . . FK PACKAGE (TOP VIEW)



NC - No internal connection

logic symbol†



[†] This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

Pin numbers shown are for the D, DB, J, N, PW, and W packages.

logic diagram, each gate (positive logic)





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absolute maximum ratings over operating free-air temperature range (unless otherwise noted)

Supply voltage range, V _{CC}		$\dots \dots -0.5 \text{ V to 7 V}$
Input voltage range, V _I (see Note 1)		$-0.5 \text{ V to V}_{CC} + 0.5 \text{ V}$
Output voltage range, VO (see Note 1)		$-0.5 \text{ V to V}_{CC} + 0.5 \text{ V}$
Input clamp current, I_{IK} ($V_I < 0$ or $V_I > V_{CC}$)		±20 mA
Output clamp current, I _{OK} (V _O < 0 or V _O > V _{CC})		±20 mA
Continuous output current, I_O ($V_O = 0$ to V_{CC})		±50 mA
Continuous current through V _{CC} or GND		±200 mA
Maximum power dissipation at $T_A = 55^{\circ}$ C (in still air) (see Note 2	2): D package	1.25 W
	DB package	0.5 W
	N package	1.1 W
	PW package	0.5 W
Storage temperature range, T _{stg}		65°C to 150°C

[†] Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTES: 1. The input and output voltage ratings may be exceeded if the input and output current ratings are observed.

recommended operating conditions (see Note 3)

			SN54/	SN54AC32		AC32	UNIT	
			MIN	MAX	MIN	MAX	JIVII	
VCC	Supply voltage		2	6	2	6	V	
	IH High-level input voltage	V _{CC} = 3 V	2.1		2.1			
V_{IH}		V _{CC} = 4.5 V	3.15		3.15		V	
		V _{CC} = 5.5 V	3.85		3.85			
		V _{CC} = 3 V		0.9		0.9		
V_{IL}	Low-level input voltage	V _{CC} = 4.5 V		1.35		1.35	V	
		V _{CC} = 5.5 V		1.65		1.65]	
٧ _I	Input voltage		0	VCC	0	VCC	V	
VO	Output voltage		0	VCC	0	VCC	V	
		V _{CC} = 3 V		-12		-12		
loH	High-level output current	V _{CC} = 4.5 V		-24		-24	mA	
		V _{CC} = 5.5 V		-24		-24		
		V _{CC} = 3 V		12		12		
lOL	Low-level output current	V _{CC} = 4.5 V		24		24	mA	
	$V_{CC} = 5.5 \text{ V}$			24		24		
Δt/Δν	Input transition rise or fall rate		0	8	0	8	ns/V	
TA	Operating free-air temperature		-55	125	-40	85	°C	

NOTE 3: Unused inputs must be held high or low to prevent them from floating.



^{2.} The maximum package power dissipation is calculated using a junction temperature of 150°C and a board trace length of 750 mils, except for the N package, which has a trace length of zero.

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST CONDITIONS	T.,	Т	A = 25°C	;	SN54	AC32	SN74AC32		UNIT		
FAI	TAKAWETEK	TEST CONDITIONS	VCC	MIN	TYP	MAX	MIN	MAX	MIN	MAX	UNIT	
			3 V	2.9			2.9		2.9			
		I _{OH} = -50 μA	4.5 V	4.4			4.4		4.4			
			5.5 V	5.4			5.4		5.4			
\ _{\\\\\\\\\\\\\\\\\\\\\\\\\\\\\\\\\\\\}		I _{OH} = – 12 mA	3 V	2.56			2.4		2.46		V	
VOH	VOH	I _{OH} = – 24 mA	4.5 V	3.86			3.7		3.76		v	
		10H = - 24 IIIA	5.5 V	4.86			4.7		4.76			
	$I_{OH} = -50 \text{ mA}^{\dagger}$	5.5 V				3.85						
		I _{OH} = -75 mA [†]	5.5 V						3.85			
			3 V		0.002	0.1		0.1		0.1		
		I _{OL} = 50 μA	4.5 V		0.001	0.1		0.1		0.1		
			5.5 V		0.001	0.1		0.1		0.1		
\ _{\\\\\\\\\\\\\\\\\\\\\\\\\\\\\\\\\\\\}	M	I _{OL} = 12 mA	3 V			0.36		0.5		0.44	V	
VOL		1a. 24 mA	4.5 V			0.36		0.5		0.44		
		I _{OL} = 24 mA	5.5 V			0.36		0.5		0.44		
		I _{OL} = 50 mA [†]	5.5 V					1.65				
		I _{OL} = 75 mA [†]	5.5 V							1.65		
II	A or B ports	V _I = V _{CC} or GND	5.5 V			±0.1		±1		±1	μΑ	
Icc		$V_I = V_{CC}$ or GND, $I_O = 0$	5.5 V			2		40		20	μΑ	
Ci		V _I = V _{CC} or GND	5 V		2.6						pF	

T Not more than one output should be tested at a time, and the duration of the test should not exceed 2 ms.

switching characteristics over recommended operating free-air temperature range, V_{CC} = 3.3 V $\,\pm\,$ 0.3 V (unless otherwise noted) (see Figure 1)

PARAMETER	FROM TO (OUTPUT)	то		4 = 25°C	;	SN54/	AC32	SN74	AC32	UNIT
		MIN	TYP	MAX	MIN	MAX	MIN	MAX	UNIT	
t _{PLH}	A or B	or P	1.5	7	9	1	12	1.5	10	no
t _{PHL}		ī	1.5	7	8.5	1	11.5	1	9	ns

switching characteristics over recommended operating free-air temperature range, V_{CC} = 5 V $\,\pm\,$ 0.5 V (unless otherwise noted) (see Figure 1)

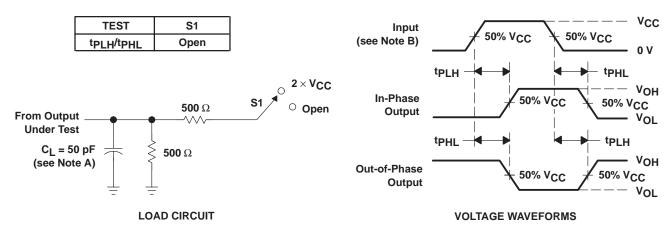
PARAMETER	FROM	то	T,	4 = 25°C	;	SN54/	AC32	SN74	AC32	UNIT
	(INPUT)	(OUTPUT)	MIN	TYP	MAX	MIN	MAX	MIN	MAX	UNIT
^t PLH	A or B	V	1.5	5.5	7.5	1	9	1	8.5	no
t _{PHL}		· ·	1.5	5	7	1	8.5	1	7.5	ns

operating characteristics, $V_{CC} = 5 \text{ V}$, $T_A = 25^{\circ}\text{C}$

PARAMETER	TEST CONDITIONS	TYP	UNIT
C _{pd} Power dissipation capacitance	$C_L = 50 \text{ pF}, f = 1 \text{ MHz}$	40	pF



PARAMETER MEASUREMENT INFORMATION



NOTES: A. C_I includes probe and jig capacitance.

- B. All input pulses are supplied by generators having the following characteristics: PRR \leq 1 MHz, $Z_O = 50 \Omega$, $t_\Gamma \leq 2.5$ ns, $t_f \leq 2.5$ ns.
- C. The outputs are measured one at a time with one input transition per measurement.

Figure 1. Load Circuit and Voltage Waveforms

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